

PSMN1R0-30YLD

N-channel 30 V, 1.0 m Ω logic level MOSFET in LFPAK56 using NextPowerS3 Technology

7 October 2013

Objective data sheet

1. General description

Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETs with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

2. Features and benefits

- Ultra low Q_G, Q_{GD} and Q_{OSS} for high system efficiency, especially at higher switching frequencies
- Superfast switching with soft-recovery; s-factor > 1
- Low spiking and ringing for low EMI designs
- Unique "SchottkyPlus" technology; Schottky-like performance with < 1 μA leakage at 25 °C
- Optimised for 4.5 V gate drive
- Low parasitic inductance and resistance
- High reliability clip bonded and solder die attach Power SO8 package; no glue, no wire bonds, gualified to 175 °C
- Wave solderable; exposed leads for optimal visual solder inspection

3. Applications

- On-board DC-to-DC solutions for server and telecommunications
- Secondary-side synchronous rectification in telecommunication applications
- Voltage regulator modules (VRM)
- Point-of-Load (POL) modules
- Power delivery for V-core, ASIC, DDR, GPU, VGA and system components
- Brushed and brushless motor control
- Power OR-ing

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C		-	-	30	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 10 V; <u>Fig. 1</u>	[1]	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	-	238	W





Symbol	Parameter	Conditions		Min	Тур	Max	Unit
T _j	junction temperature			-55	-	175	°C
Static charac	teristics		'				
R _{DSon}	drain-source on-state	V_{GS} = 4.5 V; I_{D} = 25 A; T_{j} = 25 °C		-	1.14	1.3	mΩ
	resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C		-	0.9	1.02	mΩ
Dynamic characteristics							
Q_{GD}	gate-drain charge	V_{GS} = 4.5 V; I_D = 25 A; V_{DS} = 15 V; Fig. 7		-	[tbd]	-	nC
Q _{G(tot)}	total gate charge	V_{GS} = 4.5 V; I_D = 25 A; V_{DS} = 15 V; Fig. 7		-	[tbd]	-	nC
Source-drain diode							
S	softness factor	I_S = 25 A; V_{GS} = 0 V; dI_S/dt = -100 A/ μ s; V_{DS} = 15 V; Fig. 8		-	[tbd]	-	

^[1] Continuous current is limited by package.

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source	mb	D I
2	S	source	<u> </u>	
3	S	source	q j	G_U: 4
4	G	gate	و و و و	mbb076 S
mb	D	mounting base; connected to drain	1 2 3 4 LFPAK56; Power- SO8 (SOT669)	

6. Ordering information

Table 3. Ordering information

Type number	Package	е				
	Name	Description	Version			
PSMN1R0-30YLD	LFPAK56; Power-SO8	Plastic single-ended surface-mounted package (LFPAK56; Power-SO8); 4 leads	SOT669			

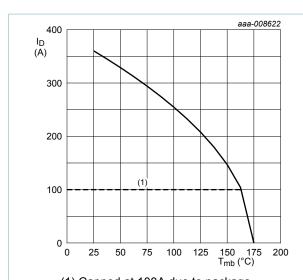
Limiting values 7.

Table 4. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C		-	30	٧
V_{DGR}	drain-gate voltage	25 °C ≤ T _j ≤ 175 °C; R _{GS} = 20 kΩ		-	30	V
V _{GS}	gate-source voltage			-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; <u>Fig. 1</u>	[1]	-	100	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; <u>Fig. 1</u>	[1]	-	100	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 \text{ °C}$		-	1441	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	238	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
T _{sld(M)}	peak soldering temperature			-	260	°C
V _{ESD}	electrostatic discharge voltage	НВМ		[tbd]	-	V
Source-dra	in diode					
I _S	source current	T _{mb} = 25 °C	[1]	-	100	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$		-	1441	Α
Avalanche	ruggedness		'	'		
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 25 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω; unclamped; t_p = 3.3 ms	[2]	-	1588	mJ

Continuous current is limited by package. Protected by 100% test



(1) Capped at 100A due to packageFig. 1. Continuous drain current as a function of

mounting base temperature

 $V_{GS} \ge 10V$

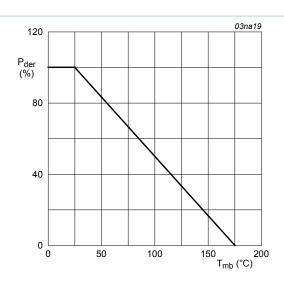


Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \,\%$$

8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 5	-	0.56	0.63	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	Fig. 3 Fig. 4	-	50 125	-	K/W K/W

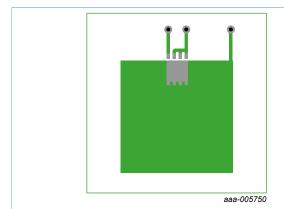


Fig. 3. PCB layout for thermal resistance junction to ambient 1" square pad; FR4 Board; 2oz copper

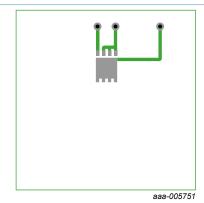
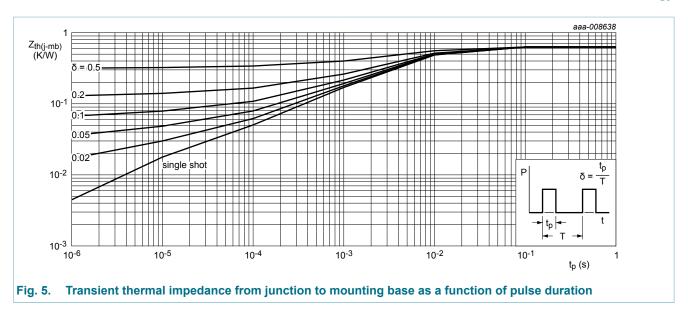


Fig. 4. PCB layout for thermal resistance junction to ambient minimum footprint; FR4 Board; 2oz copper



9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static charac	teristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	1.2	[tbd]	2.2	V
$\Delta V_{GS(th)}/\Delta T$	gate-source threshold voltage variation with temperature	25 °C ≤ T _j ≤ 150 °C	-	[tbd]	-	mV/K
I _{DSS}	drain leakage current	V _{DS} = 24 V; V _{GS} = 0 V; T _j = 25 °C	-	-	1	μA
		V _{DS} = 24 V; V _{GS} = 0 V; T _j = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	V _{GS} = 16 V; V _{DS} = 0 V; T _j = 25 °C	-	-	100	nA
		V _{GS} = -16 V; V _{DS} = 0 V; T _j = 25 °C	-	-	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C	-	1.14	1.3	mΩ
		V_{GS} = 4.5 V; I_D = 25 A; T_j = 150 °C; Fig. 6	-	-	2.15	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C	-	0.9	1.02	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 150 °C; Fig. 6	-	-	1.7	mΩ
R _G	gate resistance	f = 1 MHz	-	1.2	-	Ω

Symbol	Parameter	Conditions	Mir	т Тур	Max	Unit
Dynamic ch	naracteristics			'		
Q _{G(tot)}	total gate charge	I _D = 25 A; V _{DS} = 15 V; V _{GS} = 10 V; Fig. 7	-	[tbd]	-	nC
		I _D = 25 A; V _{DS} = 15 V; V _{GS} = 4.5 V; Fig. 7	-	[tbd]	-	nC
		I _D = 0 A; V _{DS} = 0 V; V _{GS} = 10 V	-	[tbd]	-	nC
Q_{GS}	gate-source charge	I _D = 25 A; V _{DS} = 15 V; V _{GS} = 4.5 V;	-	[tbd]	-	nC
Q _{GS(th)}	pre-threshold gate- source charge	Fig. 7	-	[tbd]	-	nC
Q _{GS(th-pl)}	post-threshold gate- source charge		-	[tbd]	-	nC
Q_{GD}	gate-drain charge		-	[tbd]	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	I _D = 25 A; V _{DS} = 15 V; <u>Fig. 7</u>	-	[tbd]	-	V
C _{iss}	input capacitance	$V_{DS} = 15 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	[tbd]	-	pF
C _{oss}	output capacitance	T _j = 25 °C	-	[tbd]	-	pF
C _{rss}	reverse transfer capacitance		-	[tbd]	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 15 V; R_L = 0.6 Ω ; V_{GS} = 4.5 V;	-	[tbd]	-	ns
t _r	rise time	$R_{G(ext)} = 5 \Omega$	-	[tbd]	-	ns
t _{d(off)}	turn-off delay time		-	[tbd]	-	ns
t _f	fall time		-	[tbd]	-	ns
Q _{oss}	output charge	$V_{GS} = 0 \text{ V}; V_{DS} = 15 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$	-	[tbd]	-	nC
Source-dra	in diode			'	-	
V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	[tbd]	1.2	V
t _{rr}	reverse recovery time	$I_S = 25 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	[tbd]	-	ns
Q _r	recovered charge	V _{DS} = 15 V; <u>Fig. 8</u>	[1] -	[tbd]	-	nC
ta	reverse recovery rise time		-	[tbd]	-	ns
t _b	reverse recovery fall time		-	[tbd]	-	ns
S	softness factor	1	-	[tbd]	-	

^[1] includes capacitive recovery

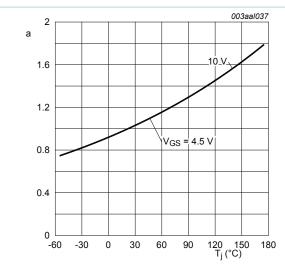


Fig. 6. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon (25^{\circ}C)}}$$

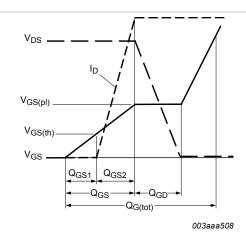


Fig. 7. Gate charge waveform definitions

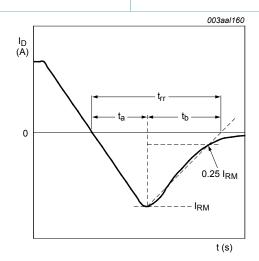
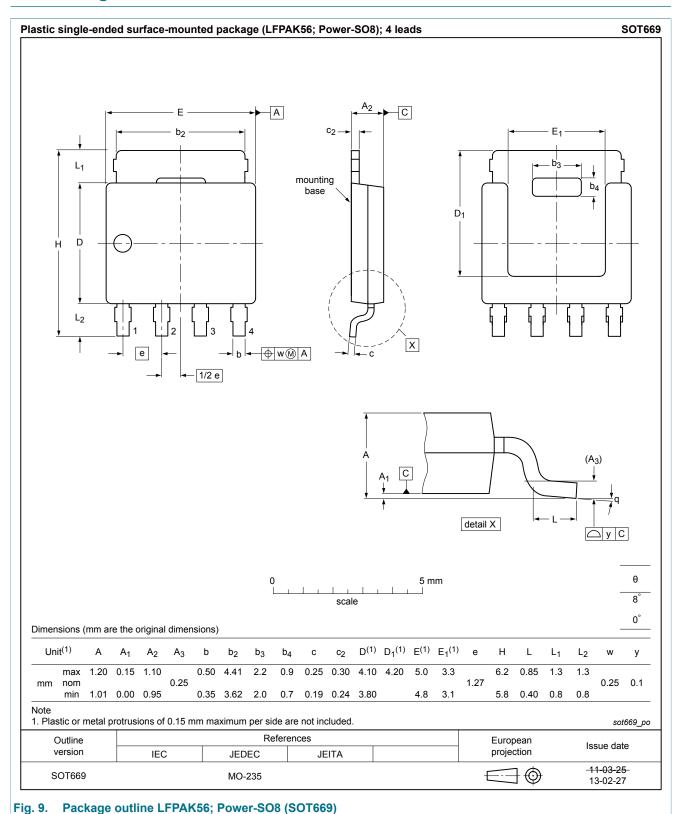


Fig. 8. Reverse recovery timing definition

10. Package outline



11. Legal information

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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